FAIRCHILD

SEMICONDUCTOR®

FDD8444_F085

N-Channel PowerTrench[®] MOSFET

40V, 50A, 5.2mΩ

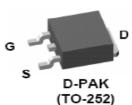
Features

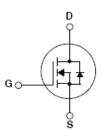
- Typ $r_{DS(on)}$ = 4m Ω at V_{GS} = 10V, I_D = 50A
- Typ Q_{g(10)} = 89nC at V_{GS} = 10V
- Low Miller Charge
- Low Q_{rr} Body Diode
- UIS Capability (Single Pulse/ Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant



Applications

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Transmission
- Distributed Power Architecture and VRMs
- Primary Switch for 12V Systems







October 2010

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain to Source Voltage		40	V
V _{GS}	Gate to Source Voltage		±20	V
	Drain Current Continuous (V _{GS} = 10V)	(Note 1)	145	
I _D	Continuous (V _{GS} = 10V, with $R_{\theta JA}$ = 52°C/W)		20	Α
	Pulsed		Figure 4	
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	535	mJ
Р	Power Dissipation		153	W
P _D	Derate above 25°C		1.02	W/ºC
TJ, T _{STG}	Operating and Storage Temperature		-55 to +175	°C

Thermal Characteristics

R_{\thetaJC}	Maximum Thermal Resistance, Junction to Case	0.98	°C/W
R_{\thetaJA}	Maximum Thermal Resistance, Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8444	FDD8444_F085	TO-252AA	13"	12mm	2500 units

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Tvp	Max	Units
• • • • • •						••

Off Characteristics

B _{VDSS}	Drain to Source Breakdown Voltage	$I_{\rm D}$ = 250 μ A, $V_{\rm GS}$ = 0V		40	-	-	V
1	Zero Gate Voltage Drain Current	V _{DS} = 32V		-	-	1	μA
DSS	Zero Gale Voltage Drain Current	$V_{GS} = 0V$	T _J = 150 ^o C	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

On Characteristics

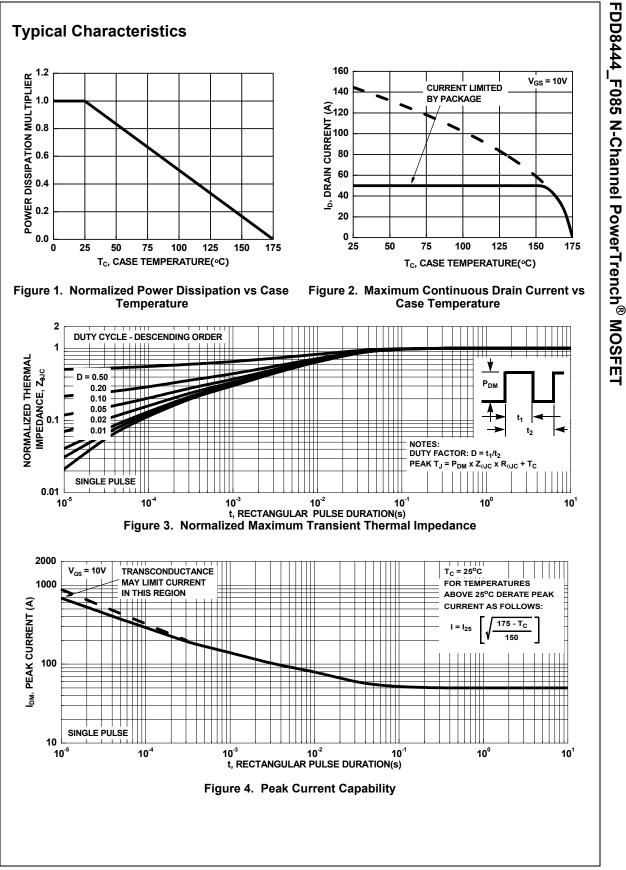
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	2.5	4	V
		I _D = 50A, V _{GS} = 10V	-	4	5.2	
r _{DS(on)}	Drain to Source On Resistance	I _D = 50A, V _{GS} = 10V, T _J = 175°C	-	7.2	9.4	mΩ

Dynamic Characteristics

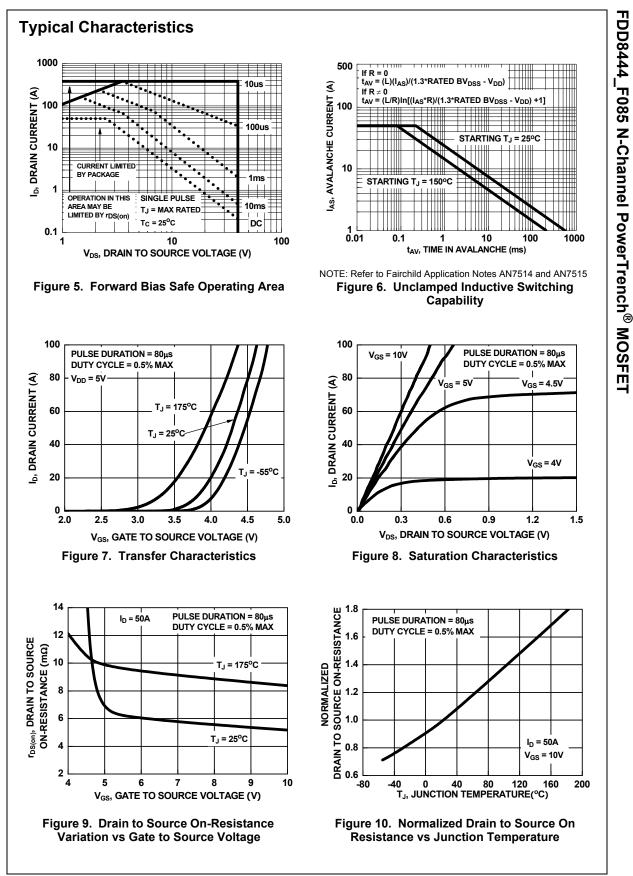
C _{iss}	Input Capacitance		0) (-	6195	-	pF
C _{oss}	Output Capacitance	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz		-	585	-	pF
C _{rss}	Reverse Transfer Capacitance			-	332	-	pF
R _G	Gate Resistance	f = 1MHz		-	1.9	-	Ω
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 0 to 10V		-	89	116	nC
Q _{g(5)}	Total Gate Charge at 5V	V_{GS} = 0 to 5V			43	56	nC
Q _{g(TH)}	Threshold Gate Charge	V_{GS} = 0 to 2V	V _{DD} = 20V I _D = 50A	-	11	14.3	nC
Q _{gs}	Gate to Source Gate Charge		$I_0 = 30A$ $I_0 = 1.0mA$	-	23	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		.y	-	11	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			-	20	-	nC

Sutching Characteristics $\frac{1}{100}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{1000}$ $\frac{1}{10000}$ $\frac{1}{100000}$ $\frac{1}{10000000000000000000000000000000000$	Turn-On Time Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Turn-Off Time in-Source Diode Characterist Source to Drain Diode Voltage Reverse Recovery Time	V _{GS} = 10V, R _{GS} = 2Ω	-	12 78 48 15	-	ns ns ns
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	Source to Drain Diode Voltage Reverse Recovery Time			-	95	ns
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VSD Source to Drain Diode Voltage ISD = 25A - 0.8 1.0 I_{rr} Reverse Recovery Time IF = 50A, dIF/dt = 100A/µs - 39 51 Qrr Reverse Recovery Charge IF = 50A, dIF/dt = 100A/µs - 45 59 Notes: : Package current limitation is 50A. - - -	Reverse Recovery Time		-	0.9	1.25	
rr Reverse Recovery Time I I - 39 51 Q_{rr} Reverse Recovery Charge I F 50A, dI - 45 59 Iotes: : Package current limitation is 50A.			-	0.8	1.0	V
$I_F = 50A, dI_F/dt = 100A/\mu s$ - 45 59 Interse Recovery Charge IF = 50A, dI_F/dt = 100A/ μ s - 45 59 Interse State S			-	39	51	ns
lotes: : Package current limitation is 50A.	Reverse Recovery Unarge	$I_F = 50A, dI_F/dt = 100A/\mu s$	-	45	59	nC

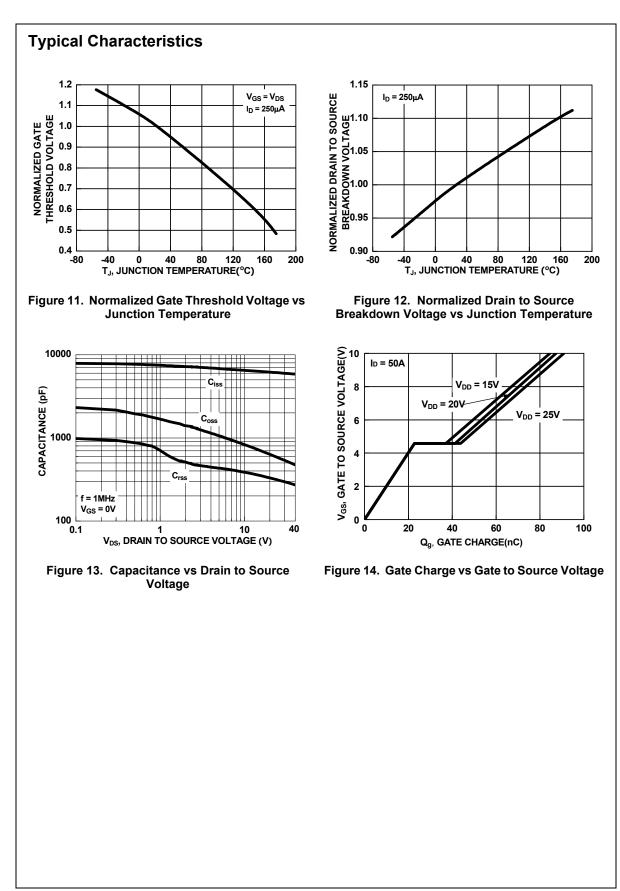
This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/ All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

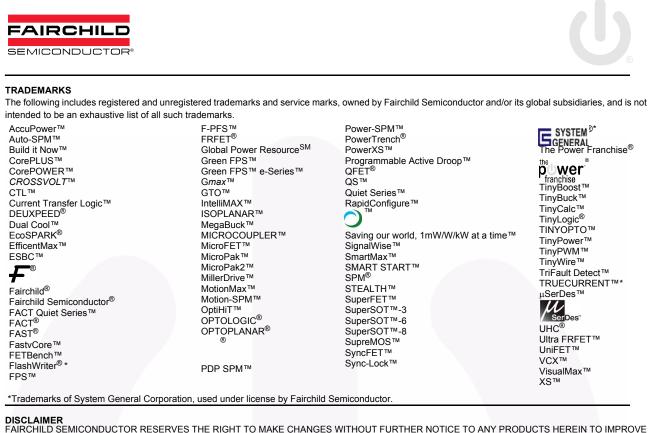


FDD8444_F085 Rev C (W)



FDD8444_F085 Rev C (W)





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